

Simulations of Silicon Radiation Detectors for HEP Experiments

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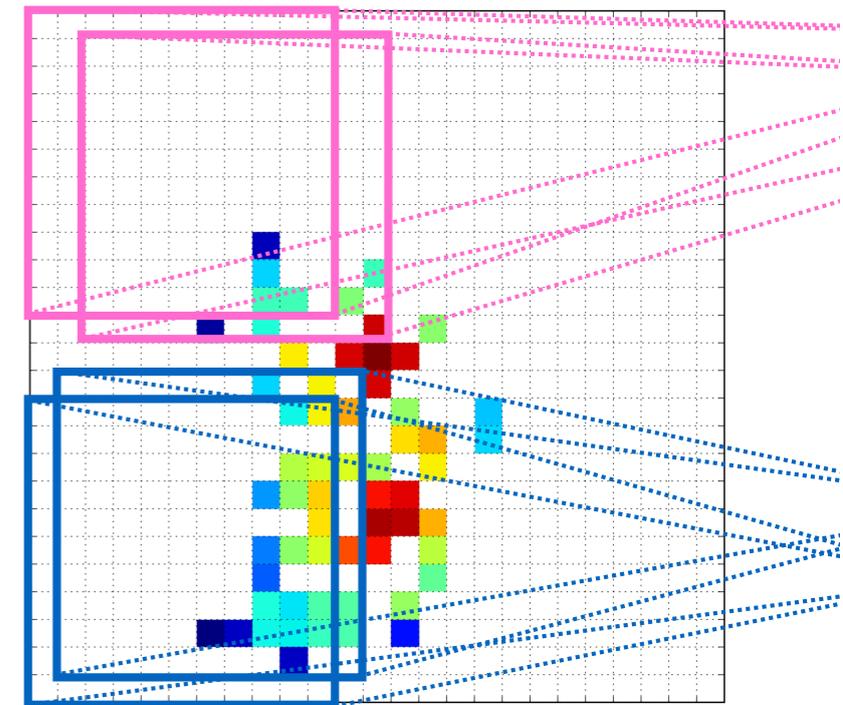
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bnachman



Snowmass IF3

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Simulations of Silicon Radiation Detectors for High Energy Physics Experiments

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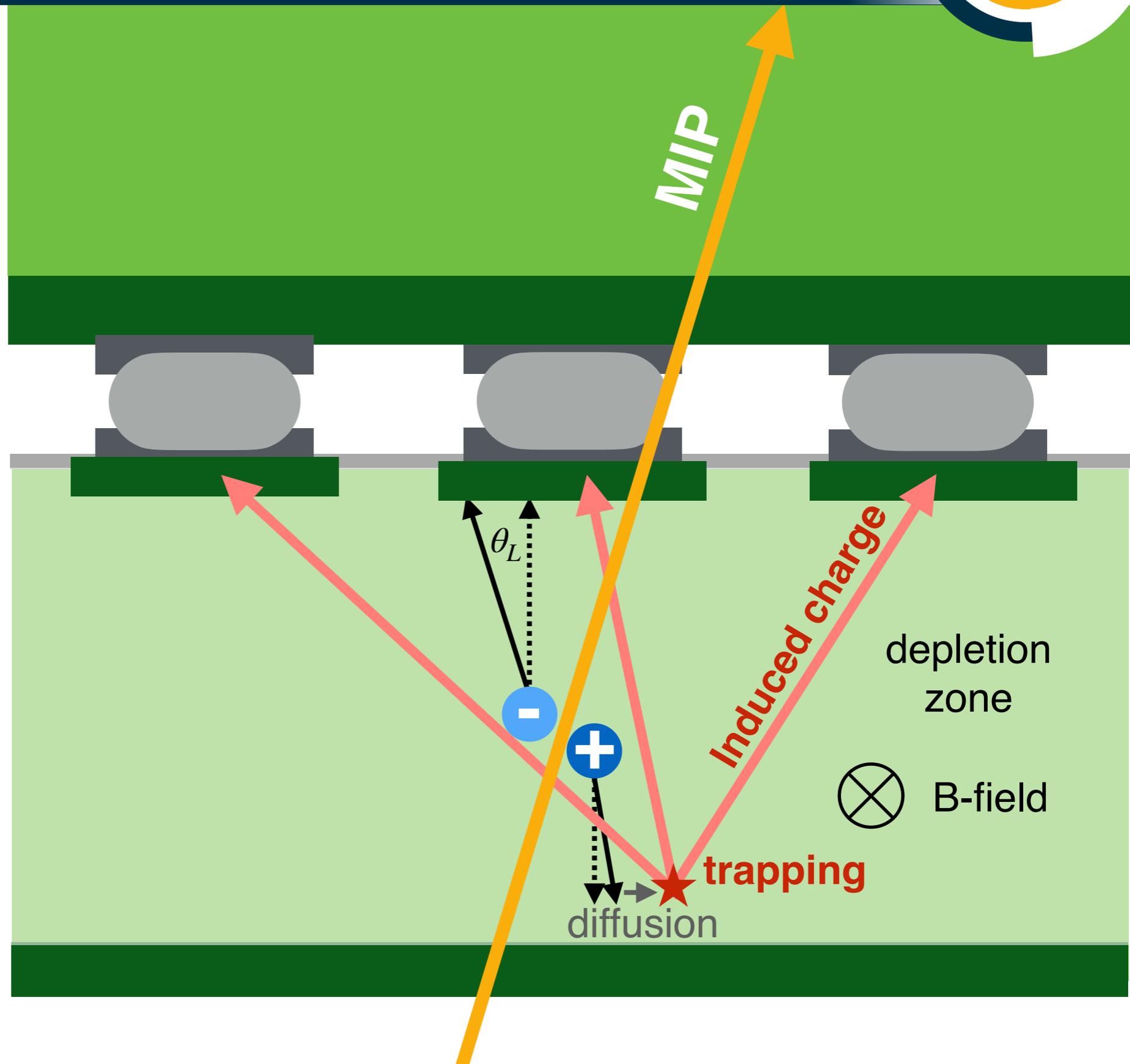
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ABSTRACT: Silicon radiation detectors are an integral component of current and planned collider experiments in high energy physics. Simulations of these detectors are essential for deciding operational configurations, for performing precise data analysis, and for developing future detectors. In this white paper, we briefly review the existing tools and discuss challenges for the future that will require research and development to be able to cope with the foreseen extreme radiation environments of the High Luminosity runs of the Large Hadron Collider and future hadron colliders like FCC-hh and SPPC.

Overview



Overview

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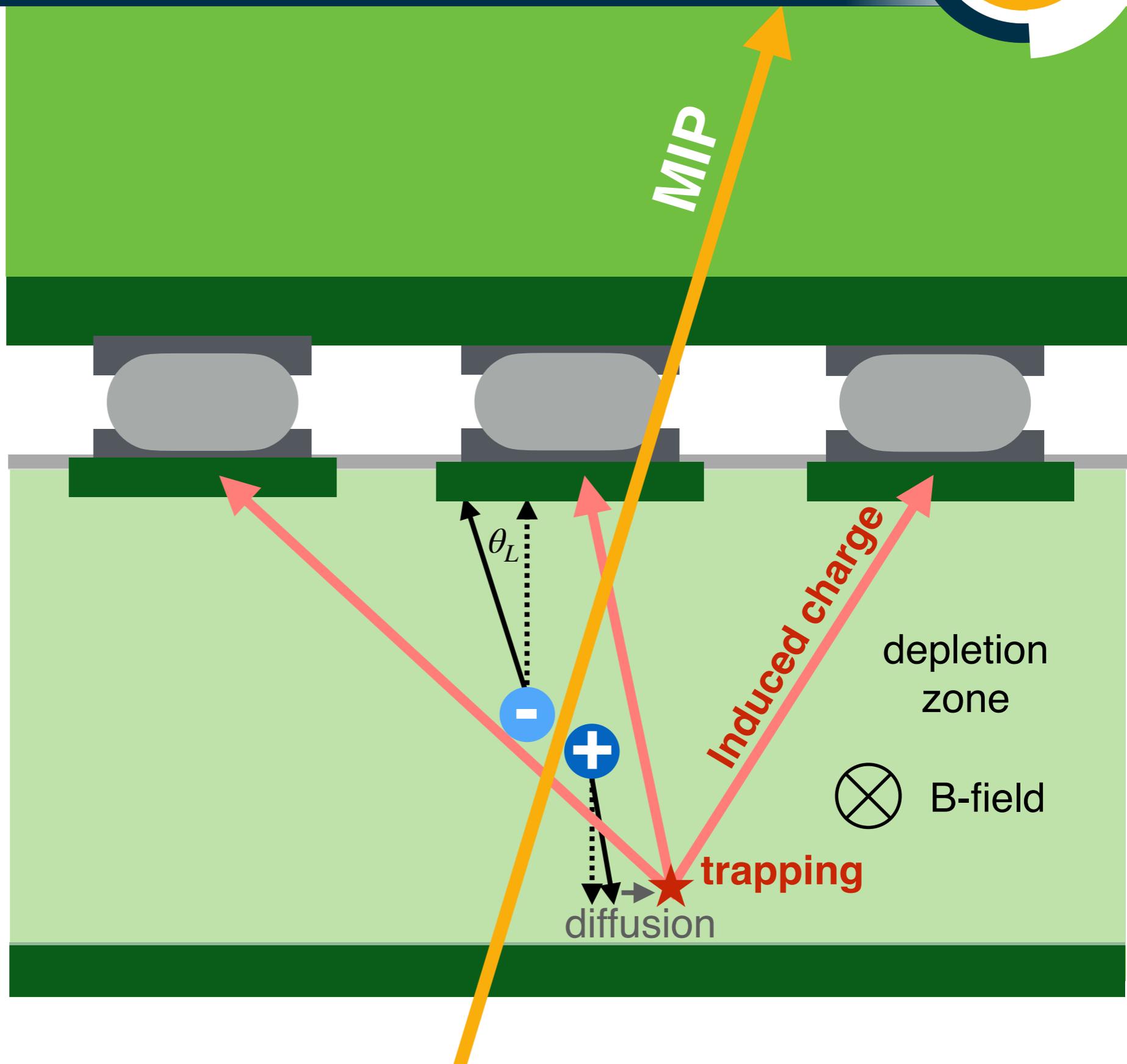
Pythia+
Geant4/FLUKA
for fluence

TCAD for
E-field

Hamburg
Model for
annealing

Modified drift-
diffusion

Detector-specific +
generic (e.g. Allpix²)



Overview

5

Pythia+

Geant4/FLUKA
for fluence

TCAD for
E-field

Hamburg
Model for
annealing

Modified drift-
diffusion

Detector-specific +
generic (e.g. Allpix²)

A mix of R&D and “engineering”.
Work being done within
collaborations and in RD50.





BNL, Brown, Fermilab, LBNL, New Mexico, Santa Cruz, Syracuse

neering".
within
RD50.

E-field

Hamburg
Model for
annealing

Modified drift-
diffusion

Detector-specific +
generic (e.g. Allpix²)



RD50



Flux Simulation



Physics modeling

Particle multiplicity, energy, composition

↓ *Pythia*

Caution:
Tuned to data, but still significant uncertainty (PDFs, MEs, frag., etc.)

Transport model

Geometry and Particle transport

↓ *FLUKA or Geant4*

Caution:

Largely unknown due in part to the availability of monochromatic beams and uncertainty in converting to 1 MeV n_{eq}

Damage factors

Non-ionizing damage

↓ *RD50 damage factors*

(more on this later)

Predicted Φ

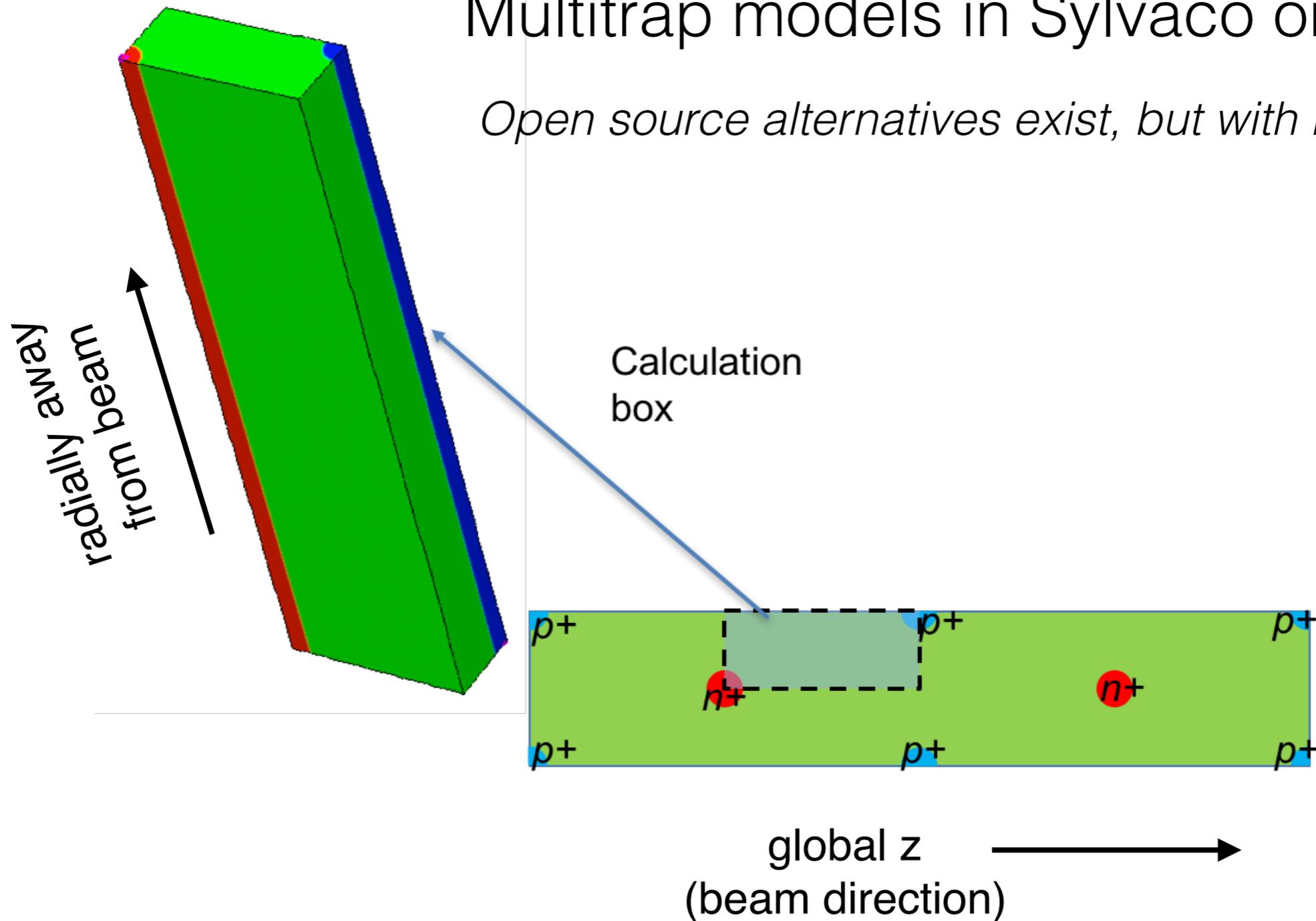
(this is only for NIEL, but similar story for SEUs and ionizing energy loss)

Device Properties (no annealing)

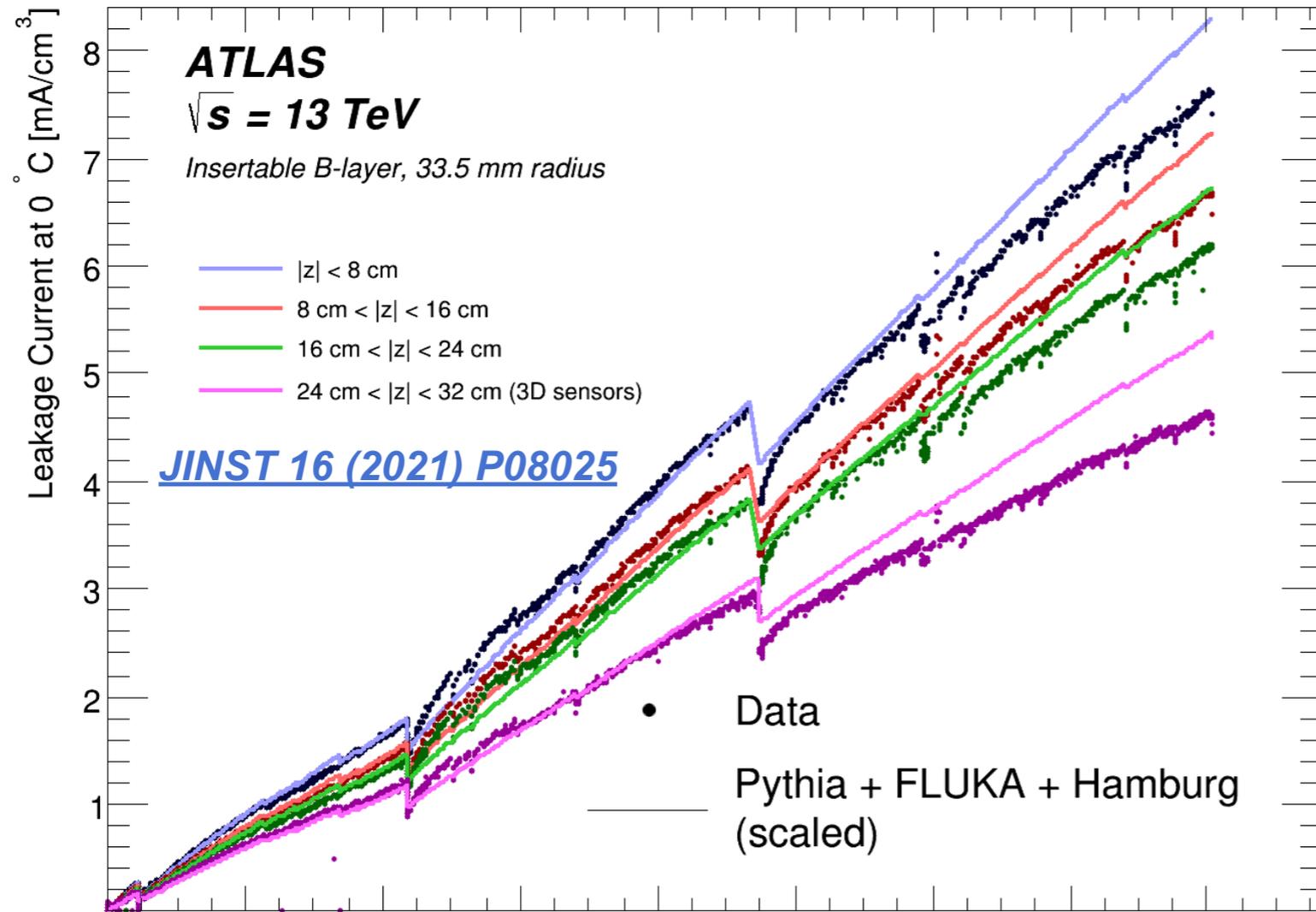


Multitrap models in Silvaco or Synopsis

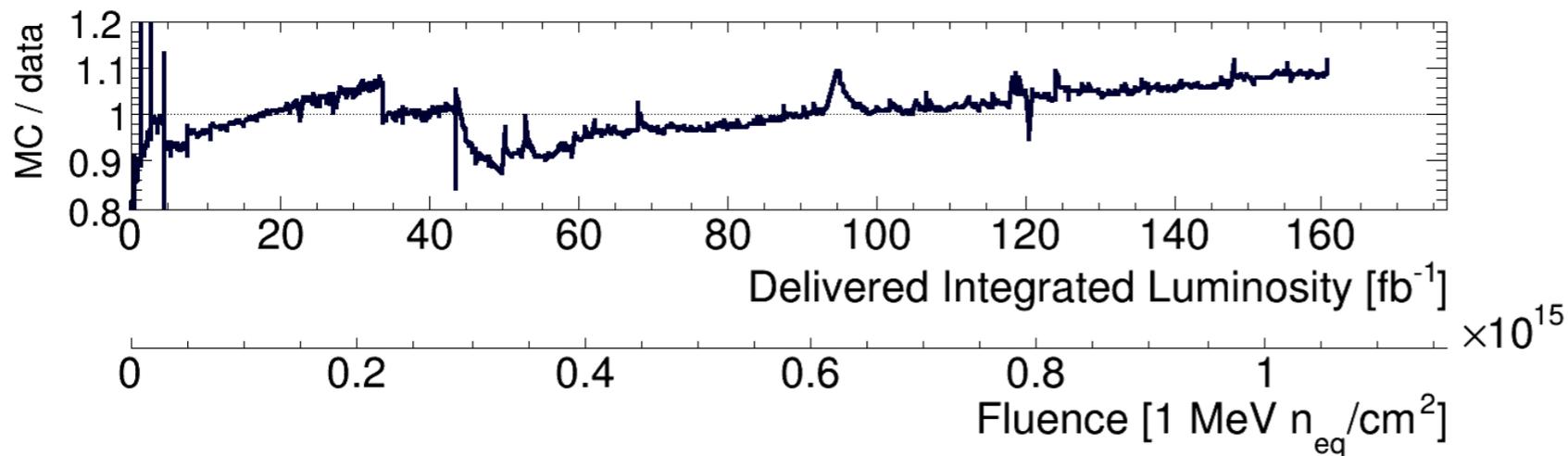
Open source alternatives exist, but with less precision



Device Properties (with annealing)



Simplified model with multi-trap states (no relation to the previous page) - different models for leakage current and depletion voltage



Full Detector Systems

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Energy
Deposition

Bichsel Model
+ G4 (δ -rays)

Geant4

Geant4

Energy
spreading

from Bichsel
+ chunking

from
Geant4

Uniform (space) +
uniform/Gauss (E)

E-field/
Lorentz angle

uniform

uniform

N/A

Diffusion

Einstein

Einstein

tuned

Noise

capacitive
coupling + noise

not discussed

capacitive
coupling + noise

Radiation
damage

none

none

none

Full Detector Systems + Rad Damage

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Energy
Deposition

Bichsel Model
+ G4 (δ -rays)

Pixelav
(applied as
correction to G4)

Geant4

Energy
spreading

from Bichsel
+ chunking

from Bichsel
+ chunking

Uniform (space) +
uniform/Gauss (E)

E-field/
Lorentz angle

TCAD
(Chiochia et al.)

TCAD
(tuned to data)

N/A

Diffusion

Einstein

Einstein

tuned

Noise

capacitive
coupling + noise

not discussed

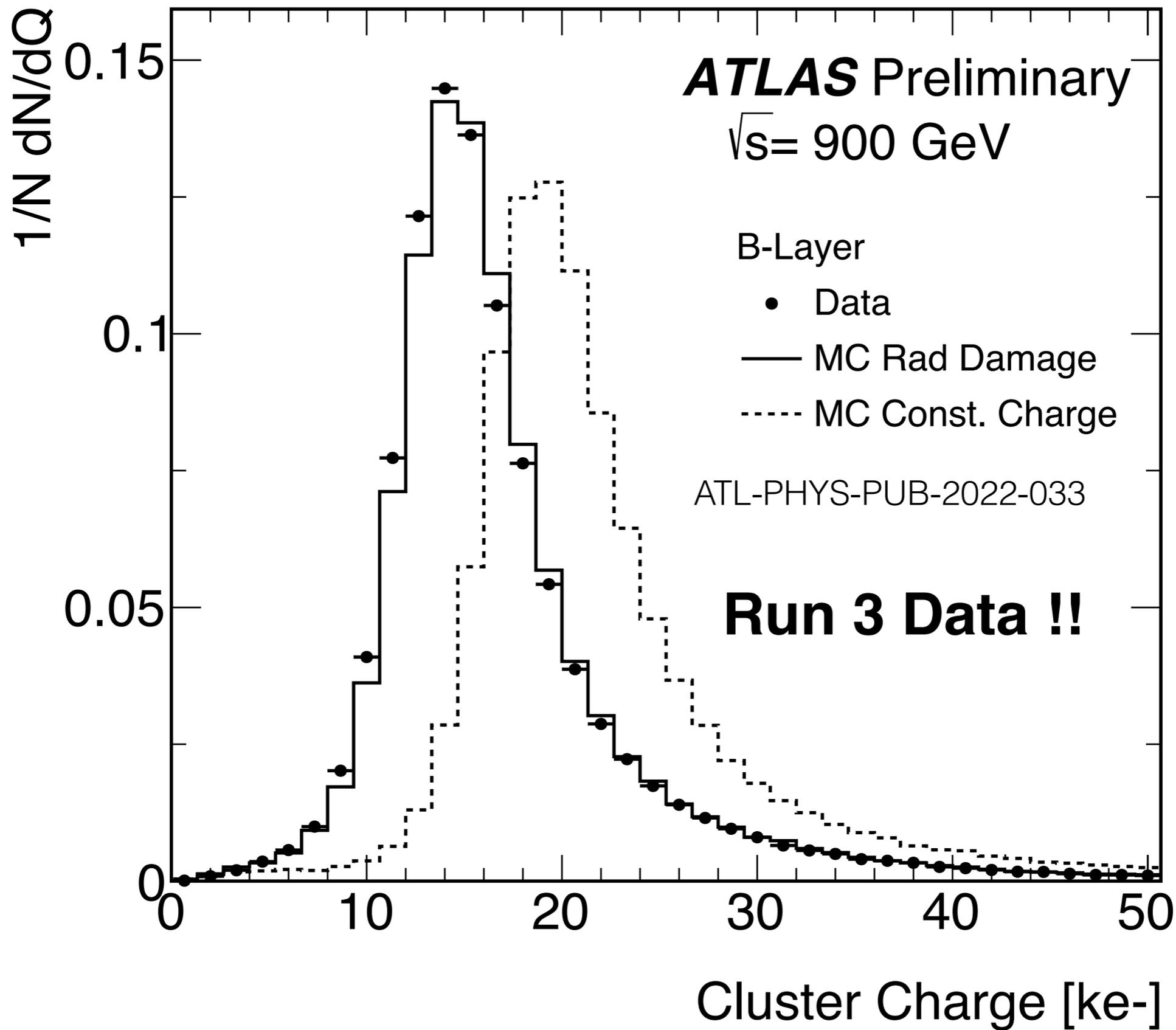
capacitive
coupling + noise

Radiation
damage

**trapping +
charge induction**

**trapping +
charge induction**

**charge & 'diffusion'
corrections**



- Proprietary Software (TCAD)
- Computational requirements for TCAD
- TCAD Uncertainties?
- TCAD + Annealing?
- Damage Model Uncertainty?
- New Effects / Devices for future colliders?

There are currently a variety of tools available for simulating the properties of silicon sensors before and after irradiation. These tools include finite element methods for device properties, dedicated annealing models, and testbeam/full detector system models. No one model can describe all of the necessary physics. Most of these models are either fully or partially developed by HEP scientists and while there are many open-source tools, the most precise device property simulations rely on expensive, proprietary software.

The development of these simulations happens inside existing experimental collaborations and within the RD50 Collaboration at CERN. RD50 is essential for model research and development and provides an important forum for inter-collaboration exchange.

While existing approaches are able to describe many aspects of signal formation in silicon devices, even after irradiation and annealing, there is significant research and development (R&D) required to improve the accuracy and precision of these models and to be able to handle new devices (e.g. for timing) and the extreme fluences of future colliders. The US particle physics community can play a key role in this R&D program, but it will require resources for training, software, testbeam, and personnel.

For example, there is a great need for (1) a unified microscopic model of sensor charge collection, radiation damage, and annealing (no model can currently do all three), (2) radiation damage models (for leakage current, depletion voltage, charge collection) with uncertainties (and a database of such models), and (3) a measurement program to determine damage factors and uncertainties for particle types and energies relevant for current and future colliders.

Executive Summary

There are currently a variety of tools available for simulating the properties of silicon sensors before and after irradiation. These tools include finite element methods for device properties, dedicated annealing models, and testbeam/full detector system models. No one model can describe all of the necessary physics. Most of these models are either fully or partially developed by HEP scientists and while there are many open-source tools, the most precise device property simulations rely on expensive, proprietary software.

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Backup

